

## P-Channel Enhancement Mode Mosfet

### GENERAL DESCRIPTION

The ME2345 is the P-Channel logic enhancement mode power field effect transistors are produced using high cell density , DMOS trench technology. This high density process is especially tailored to minimize on-state resistance. These devices are particularly suited for low voltage application such as cellular phone and notebook computer power management and other battery powered circuits where high-side switching and low in-line power loss are needed in a very small outline surface mount package.

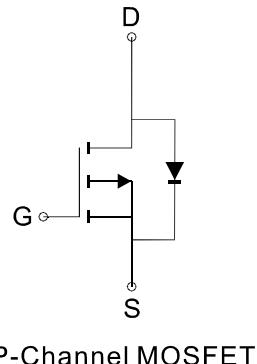
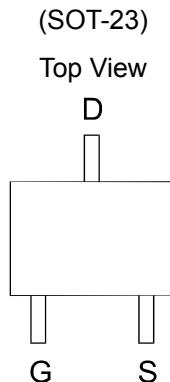
### FEATURES

- $R_{DS(ON)} \leq 65m\Omega @ V_{GS}=-10V$
- $R_{DS(ON)} \leq 75m\Omega @ V_{GS}=-4.5V$
- $R_{DS(ON)} \leq 105m\Omega @ V_{GS}=-2.5V$
- Super high density cell design for extremely low  $R_{DS(ON)}$
- Exceptional on-resistance and maximum DC current capability

### APPLICATIONS

- Power Management in Note book
- Portable Equipment
- Battery Powered System
- Load Switch
- DSC

### PIN CONFIGURATION



Ordering Information: ME2345 (Pb-free)

ME2345-G (Green product-Halogen free) (Green

### Absolute Maximum Ratings ( $T_A=25^\circ C$ Unless Otherwise Noted)

Parameter	Symbol	Limit		Unit
Drain-Source Voltage	$V_{DSS}$	-30		V
Gate-Source Voltage	$V_{GSS}$	$\pm 12$		V
Continuous Drain Current( $T_j=150^\circ C$ )*	$I_D$	-3.65		A
$T_A=70^\circ C$		-2.9		
Pulsed Drain Current	$I_{DM}$	-15		A
Maximum Power Dissipation*	$P_D$	1.4		W
$T_A=25^\circ C$		0.9		
Operating Junction Temperature	$T_J$	-55 to 150		°C
Thermal Resistance-Junction to Ambient*	$R_{\theta JA}$	$T \leq 10 \text{ sec}$	90	°C/W
Steady State			120	

\* The device mounted on 1in<sup>2</sup> FR4 board with 2 oz copper, the current rating is based on  $t \leq 10 \text{ sec}$   $R_{\theta JA}$  rating.

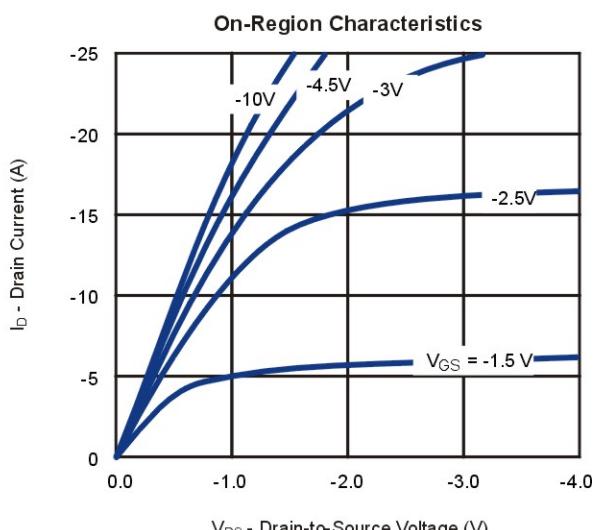
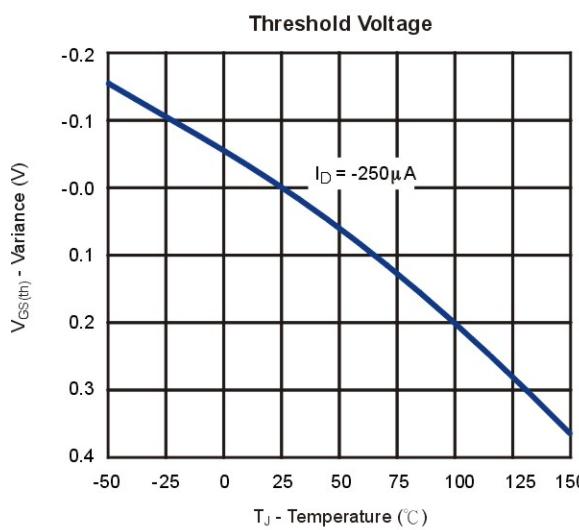
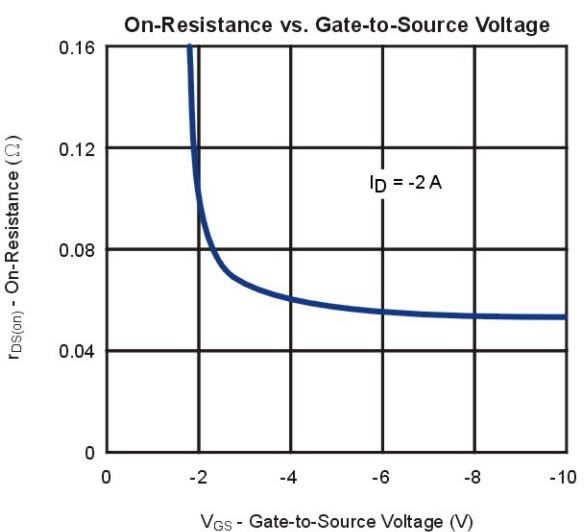
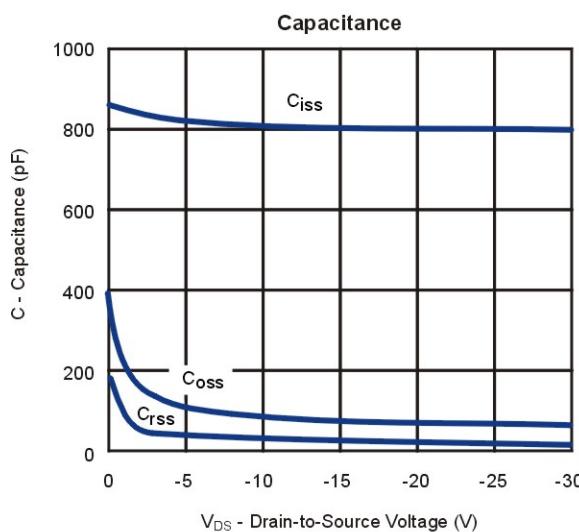
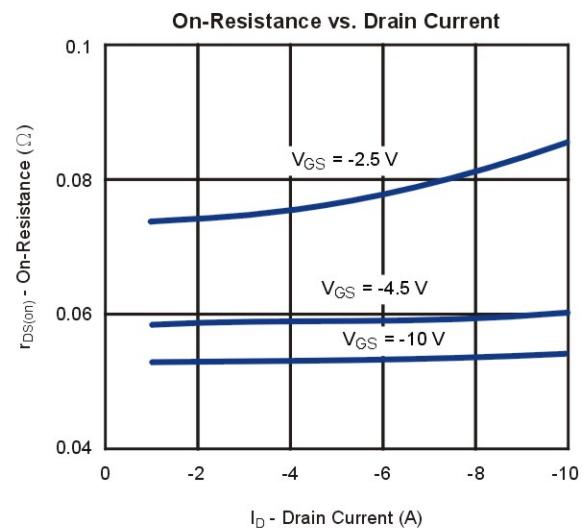
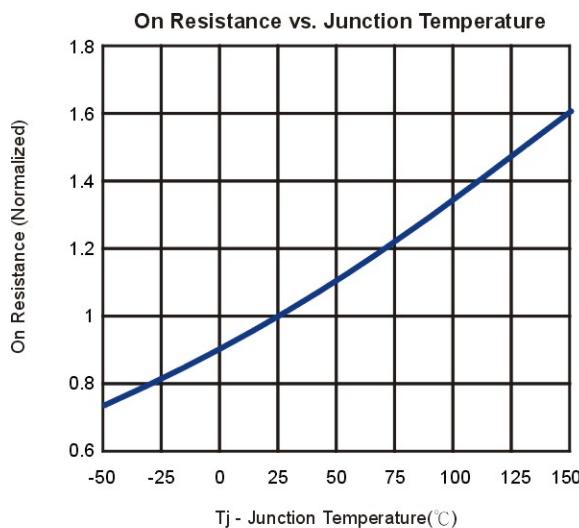
## P-Channel Enhancement Mode Mosfet

**Electrical Characteristics (TA = 25°C Unless Otherwise Specified)**

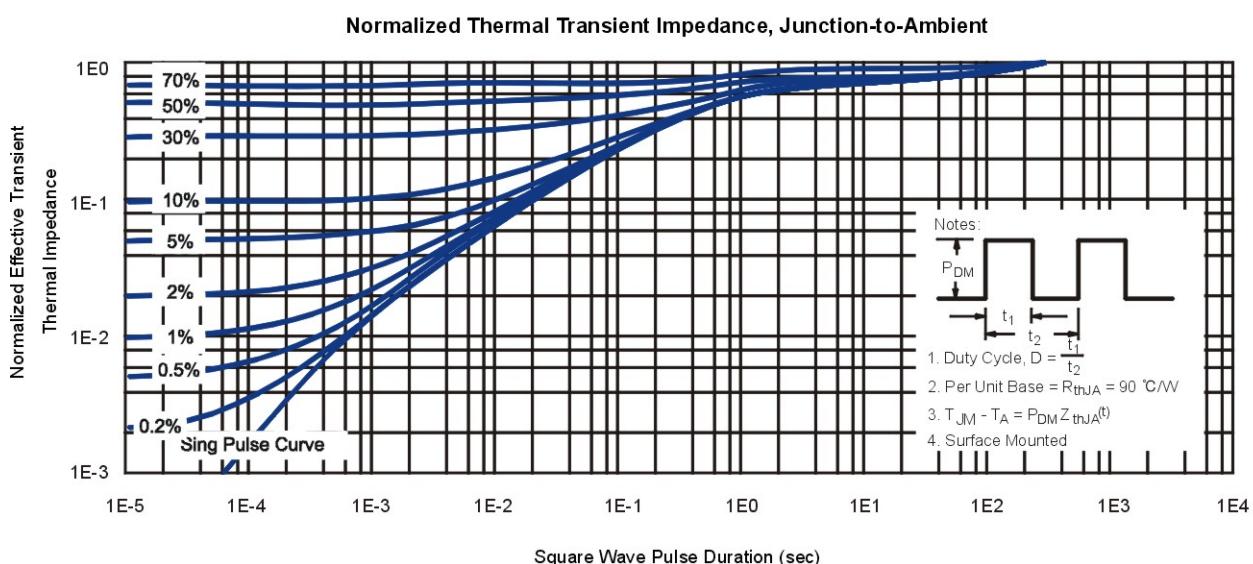
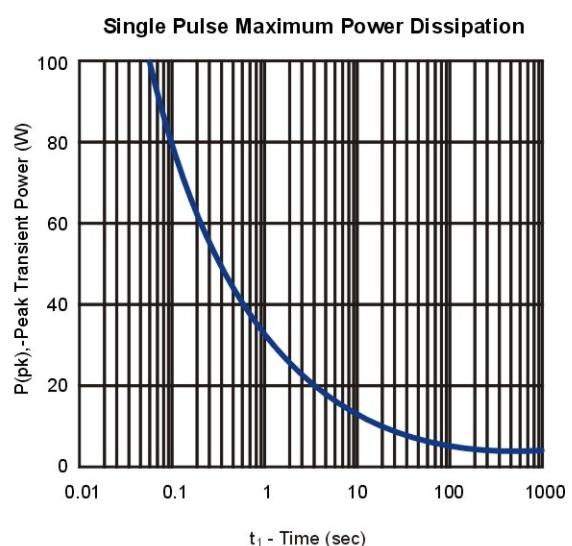
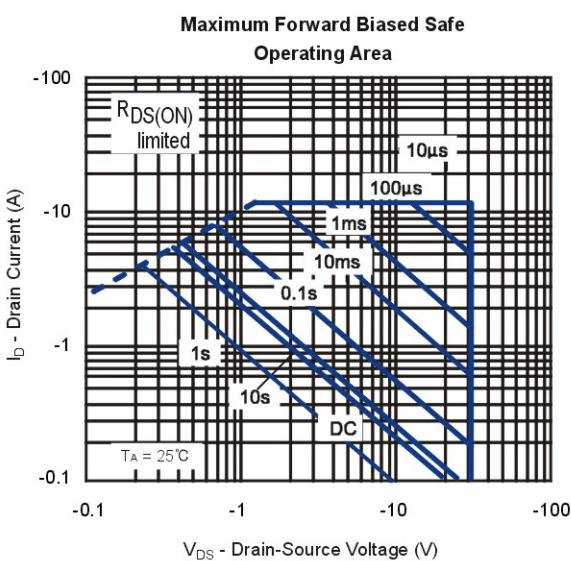
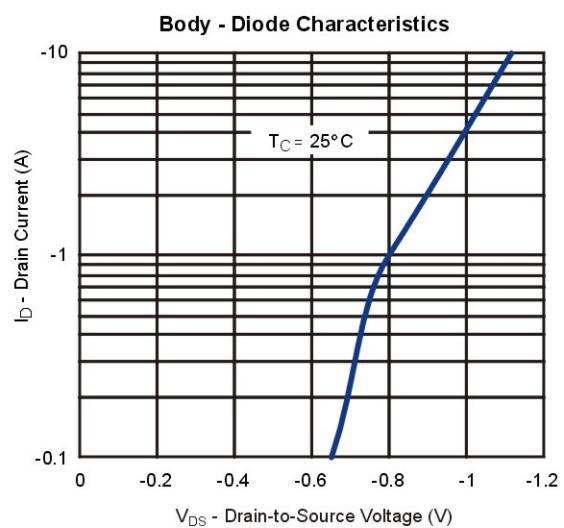
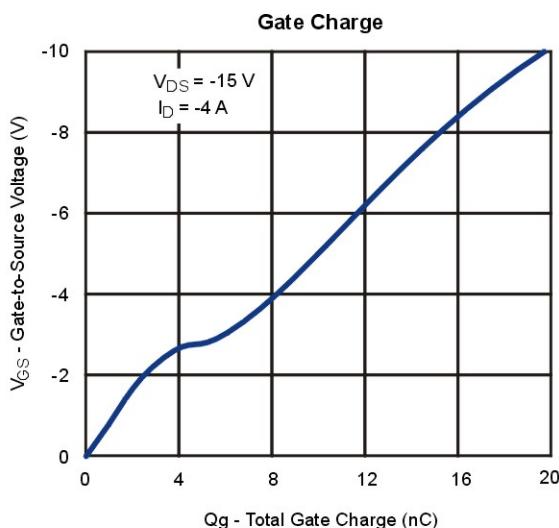
Symbol	Parameter	Limit	Min	Typ	Max	Unit
<b>STATIC</b>						
V <sub>(BR)DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =-250 μA	-30			V
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =-250 μA	-0.7		-1.3	V
I <sub>GSS</sub>	Gate Leakage Current	V <sub>DS</sub> =0V, V <sub>GS</sub> =±12V			±100	nA
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =-24V, V <sub>GS</sub> =0V			-1	μA
R <sub>DS(ON)</sub>	Drain-Source On-Resistance <sup>a</sup>	V <sub>GS</sub> =-10V, I <sub>D</sub> = -4.2A		53	65	mΩ
		V <sub>GS</sub> =-4.5V, I <sub>D</sub> = -4A		59	75	
		V <sub>GS</sub> =-2.5V, I <sub>D</sub> = -2A		74	105	
V <sub>SD</sub>	Diode Forward Voltage	I <sub>S</sub> =-1A, V <sub>GS</sub> =0V		-0.7	-1	V
<b>DYNAMIC</b>						
Q <sub>g</sub>	Total Gate Charge	V <sub>DS</sub> =-15V, V <sub>GS</sub> =-4.5V, I <sub>D</sub> =-4A		9.5		nC
Q <sub>gs</sub>	Gate-Source Charge			3		
Q <sub>gd</sub>	Gate-Drain Charge			2		
R <sub>g</sub>	Gate-Resistance	V <sub>DS</sub> =0V, V <sub>GS</sub> =0V, F=1MHz		5.5		Ω
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> =-15V, V <sub>GS</sub> =0V, f=1MHz		800		pF
C <sub>oss</sub>	Output Capacitance			70		
C <sub>rss</sub>	Reverse Transfer Capacitance			20		
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DS</sub> =-15V, R <sub>L</sub> =3.6Ω R <sub>GEN</sub> =6Ω, V <sub>GS</sub> =-10V		37		ns
t <sub>r</sub>	Turn-On Rise Time			23		
t <sub>d(off)</sub>	Turn-Off Delay Time			46		
t <sub>f</sub>	Turn-Off Fall time			3		

Notes: a. Pulse test; pulse width  $\leq$  300us, duty cycle  $\leq$  2%

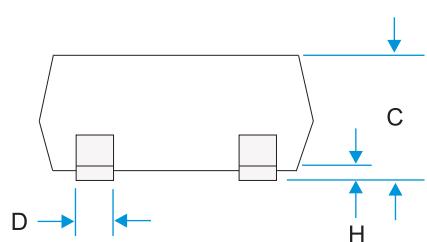
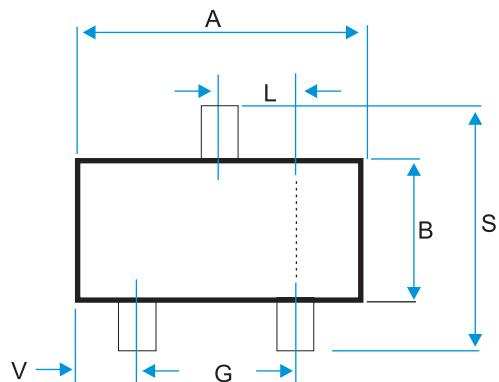
**Typical Characteristics (T<sub>J</sub> = 25°C Noted)**



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### SOT-23 Package Outline



DIM	MILLIMETERS (mm)	
	MIN	MAX
A	2.800	3.00
B	1.200	1.70
C	0.900	1.30
D	0.350	0.50
G	1.780	2.04
H	0.010	0.15
J	0.085	0.20
K	0.300	0.65
L	0.890	1.02
S	2.100	3.00
V	0.450	0.60

